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Part 21: Uncertainty evaluation in the accuracy test of instrument transformers

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Instrument transformers - Part 21: Uncertainty evaluation in the accuracy test of instrument transformers

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Draft	Report on voting
38/829/FDIS	38/835/RVD

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INTRODUCTION

Accuracy is a crucial feature of instrument transformers (ITs) in most cases and applications: its assessment is required since a very long time by the relevant International Standards, which also establish the conventional accuracy requirements in terms of accuracy classes limits.

This document aims at a) providing information on the main sources of uncertainties arising in the setup used to test the accuracy of ITs and that must be taken into account in the evaluation of measurement uncertainty; b) defining the procedures to be implemented for testing the accuracy of ITs, depending on the type of IT (i.e. either with an analogue or a digital secondary signal) and assessing the conformity to the requirements reported in the product standards (conformity assessment); c) defining the procedure for evaluating the uncertainty contributions in testing the accuracy of ITs.

1 Scope

This part of IEC 61869 provides the requirements, the methods and the guidelines to be applied on the evaluation of uncertainty in testing the accuracy of instrument transformers (IT) with an analogue or a digital secondary signal for measuring, protection and control purposes, with rated frequencies from 15 Hz to 400 Hz.

This document covers the uncertainty evaluation in testing the accuracy of IT (including on-site testing of accuracy) independently of the technology used (either inductive or non-inductive).

This document reports on how to take into account the sources of uncertainty in the setups for accuracy and how to combine their effects in order to evaluate the uncertainty in the test results. Metrological traceability to the International System of Units (SI) will always be assumed for both reference devices and devices under test.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61869 (all parts), *Instrument transformers*

IEC 61869-9, *Instrument transformers - Part 9: Digital interface for instrument transformers*

IEC 61869-99:2022, *Instrument transformers - Part 99: Glossary*

IEEE C57.13-2016, *IEEE Standard Requirements for Instrument Transformers*

JCGM 100:2008 or ISO/IEC Guide 98-3:2008, *Evaluation of measurement data - Guide to the expression of uncertainty in measurement (GUM)*

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IEC 60050-312, *International Electrotechnical Vocabulary (IEV) - Part 312: Electrical and electronic measurements and measuring instruments - General terms relating to electrical measurements,* available at https://www.electropedia.org

IEC 60060-1:2025, *High-voltage test techniques - Part 1: General terminology and test requirements*

IEC 60060-2, *High-voltage test techniques - Part 2: Measuring systems*

IEC 60060-3, *High-voltage test techniques - Part 3: Definitions and requirements for on-site testing*

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